

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
BROADRE.023CP2APPLICATION NO.
10/613976INFORMATION DISCLOSURE STATEMENT
BY APPLICANTAPPLICANT
Broadley, et al.FILING DATE
July 2, 2003GROUP
1753

(USE SEVERAL SHEETS IF NECESSARY)

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
KO	1	2,595,042	4/52	WYLLIE			
KO	2	3,445,368	5/20/69	DETEMPLE			
KO	3	3,528,904	9/70	CLIFFGARD			
KO	4	3,607,702	9/71	HALLER			
KO	5	3,756,936	9/73	NEUWELT			
KO	6	3,915,829	10/28/75	KREBS			
KO	7	3,917,523	11/4/75	STEIN, et al.			
	8	3,962,765	12/16/75	HADDAD			
KO	9	4,002,547	1/11/77	NETI et al.			
KO	10	4,012,308	3/15/77	JERROLD-JONES, et al.			
KO	11	4,177,126	12/4/79	IMAKI, et al.			
KO	12	4,366,040	12/28/82	MARSONER, et al.			
KO	13	4,495,052	1/22/85	BREZINSKI			
	14	4,592,824	6/3/86	GREGORY			
KO	15	4,592,824	6/3/86	SMITH, et al.			
KO	16	4,818,366	4/89	YONCO, et al.			
KO	17	5,360,529	11/1/94	EDWARDS, et al.			
KO	18	5,397,452	3/14/95	BUCK, et al.			
KO	19	5,632,876	5/23/97	ZANZUCCHI, et al			
KO	20	6,165,336	12/00	MAKI, et al.			

FOREIGN PATENT DOCUMENTS

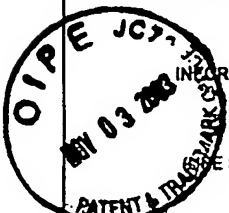
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
KO	21	WO 99/63334 A1	12/9/99	EPO				
KO	22	JP 10104193-A2	4/24/98	JAPAN			X	
KO	23	JP 11258197-A2	9/24/99	JAPAN			X	
KO	24	FR 25414624	8/24/84	FRANCE				

EXAMINER

DATE CONSIDERED

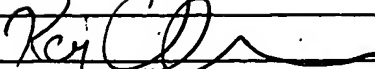
4/10/07

*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.

	FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. BROADRE.023CP2	APPLICATION NO. 10/613976
	INFORMATION DISCLOSURE STATEMENT BY APPLICANT			APPLICANT Broadley, et al.
	USE SEVERAL SHEETS IF NECESSARY)			FILING DATE July 2, 2003

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
KU	25	Brezinski, Donald, <i>Kinetic, static and stirring errors of liquid junction reference electrodes</i> , Corning Glass Works, April 1983: Vol. 108, No. 1285, pp 425-442
KO	26	Covington, et al., <i>Improvements in the precision of pH measurements a laboratory reference electrode with renewable free-diffusion liquid junction</i> . <i>Analytica Chemical Acta</i> , 169 (1985) 221-229.
KO	27	Dohner, et al., <i>Reference electrode with free-flowing free-diffusion liquid junction</i> , <i>Analytical Chemistry</i> , Vo. 68, No.12 (1986) pp. 2585-2589.
KO	28	Illingworth, John, <i>A common source of error in pH measurements</i> <i>Biochem. J.</i> (1981) 195, 259-262
KU	29	Nishizawa, M. et al., <i>Metal nanotubule membranes with electrochemically switchable ion-transport selectivity</i> ; <i>Science, American Assoc. for the Advancement of Science</i> , 268, 700-702 (1995)
KO	30	Peters, G., <i>A Reference Electrode with free-diffusion liquid junction for electrochemical measurements under changing pressure conditions</i> ; <i>Analytical Chemistry</i> , US American Chemical Society: 69:13 2362-2366 (1997)
KU	31	Suzuki, et al., <i>Microfabricated Liquid Junction Ag/AgCl Reference Electrode and Its Application to a One-Chip Potentiometric Sensor</i> , <i>Anal. Chem.</i> Vol. 71, no. 22, pp. 5069-5075, (1999)

S:\DOCS\JFK\JFK-2697.DOC:gem100603

EXAMINER		DATE CONSIDERED	4/10/07
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
BROADRE.023CP2APPLICATION NO.
10/613,976INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

(USE SEVERAL SHEETS IF NECESSARY)

APPLICANT
Broadley, S.T. et al.FILING DATE
July 2, 2003GROUP
1753

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
KO	1	GB 2 093 193 A	08/25/82	UK				
KO	2	WO 01/75430 A2	10/11/01	PCT				

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
KO	3	Hulteen, J.C. et al. (1997) A general template-based method for the preparation of nanomaterials. J. Matr. Chem. 7(7):1075-1087.

S:\DOCS\GAH\GAH-2830.DOC\081804

EXAMINER	<i>Key</i>	DATE CONSIDERED	4/10/07
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. BROADRE.23CP2	APPLICATION NO. 10/613,978
	APPLICANT Broadley, et al.	
	FILING DATE July 2, 2003	GROUP 1753

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
KO	1	3,410,779	11/12/68	Whitehead Jr., et al.			
KO	2	3,463,717	08/26/69	Koopman, et al.			
KO	3	3,677,844	07/18/72	Fleischer, et al.			
KO	4	4,886,505	12/12/89	Haynes, et al.			
KO	5	5,641,808	06/24/97	Gaffney, et al.			
	6	6,426,996	07/30/02	Fletcher, et al.			
KO	7	6,495,012	12/17/02	Fletcher, et al.			
KO	8	6,599,409	07/29/03	Broadley, et al.			
KO	9	2001/0045357	11/29/01	Broadley, et al.			
KO	10	2002/0189943	12/19/02	Fletcher, et al.			
KO	11	2003/0168354	09/11/03	Broadley, et al.			
KO	12	2003/0178305	09/25/03	Catalano, et al.			
KO	13	2004/011647	01/22/04	Broadley, et al.			
KO	14	2004/0011670	01/22/04	Broadley, et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
KO	15	EP 0 761 094 A1	03/12/97	EUROPE			X	
KO	16	DE 12 17 657 B	05/26/66	GERMANY				X
KO	17	JP 08-285811	01/11/96	JAPAN			X	

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)	
KO	18	International Search Report dated November 11, 2004 for International Application No. PCT/US03/21156.

S:\DOCS\GAH\GAH-3207.DOC/cfg/113004

EXAMINER	<i>Kay</i>	DATE CONSIDERED	4/9/07
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. BROADRE.23C1	APPLICATION NO. 10/361,708
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)		APPLICANT Broadley, et al.	GROUP 1753
		FILING DATE February 6, 2003	

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
	1	4,886,505	12/12/80	Haynes, et al.			
	2	5,641,808	06/24/97	Gaffney, et al.			
	3	6,426,005	07/30/02	Fletcher, et al.			
	4	6,495,012	12/17/02	Fletcher, et al.			
	5	6,559,409	07/20/03	Broadley, et al.			
	6	2001/0045357	11/29/01	Broadley, et al.			
	7	2002/0109943	12/19/02	Fletcher, et al.			
	8	2002/0168354	09/11/03	Broadley, et al.			
	9	2003/0178305	09/25/03	Catalano, et al.			
	10	2004/011647	01/22/04	Broadley, et al.			
	11	2004/0011670	01/22/04	Broadley, et al.			
KO	12	2004/0195098	10/07/04	Broadley, et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	13	EP 0 761 094 A1	03/12/97	EUROPE			X	
	14	DE 12 17 657 B	05/26/66	GERMANY				X

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)
	15 International Search Report dated November 11, 2004 for International Application No. PCT/US03/21156.

S:\DOCS\GAH\GAH-3213.DOC/cfg/113004

EXAMINER	<i>Kay</i>	DATE CONSIDERED	4/9/07
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.			